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## Testing Result

Num	Test item list	Result	Remark
1	Temp./humidity power on/off test	Pass	
2	Room temperature test	Pass	
3	Temperature rise test	Fail	
4	High temperature storage test	Pass	
5	High temperature operation test	Pass	
6	Low temperature storage test	Pass	
7	Low temperature operation test	Pass	
8	Humidity test	Pass	
9	Temperature shock operation test	Pass	
10	Temperature shock non-operation test	Pass	
11	Cold start and hot start test	Pass	

# Configuration of EUT

## Test Product: RTC-1000D1 + RDS-141V

### Sample Configuration & Quantity Under Test:

Num	Item	Spec
<b>RTC-1000D1</b>		
01.	<b>CPU:</b>	Intel Celeron M Processor Yonah U2500 / 1.2GHz / 1.175V / FSB:533
02.	<b>PCBA</b>	RTC-1000D.Rev.B0.1
03.	<b>BIOS</b>	RTC-1000D1 BIOS Version: 0.B
04.	<b>Memory</b>	DSL 1GB / ELPIDA E5108AJBG-6E-E / DDR2 667
05.	<b>SATA II HDD</b>	Western Digital 80GB / WD800BEVT / 5400RPM
06.	<b>WLAN + BT Module</b>	AECO-AWM-S0021M
07.	<b>LCD</b>	CPT 10.2" LCD / CLAA102NA0ACW
08.	<b>LED Driving Board</b>	LITEMAX LID10B02
09.	<b>Touch Panel</b>	AMT 10454 4-wire, Analog Resistive
10.	<b>Modem</b>	QCOM-MA560-7 / Agere SV92A3 Chipset
11.	<b>Battery</b>	LI-ION Rechargeable Battery / DR202 DC11.1V / 7800mAh
12.	<b>AC Adapter</b>	FSP FSP065 (Output: 19V / 3.42A)
13.	<b>AC Power Input</b>	110V / 60 Hz
14.	<b>Test Software</b>	Windows XP Embedded / Run Pass Mark Burn In Test 4.0 Pro
<b>RDS-141V Docking</b>		
01.	<b>AC Adapter</b>	FSP FSP065 (Output: 19V / 3.42A)
02.	<b>AC Power Input</b>	110V / 60 Hz

**Test Date:** 06-21~22-2010

**Test Model:** RTC-1000D1 Main Board only

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference IEC 68-2-30 Testing procedures  
Test Db: Damp Heat Test  
Reference IEC 68-2-1 Testing procedures  
Test Ab: Cold Test

**Test Equipment:**

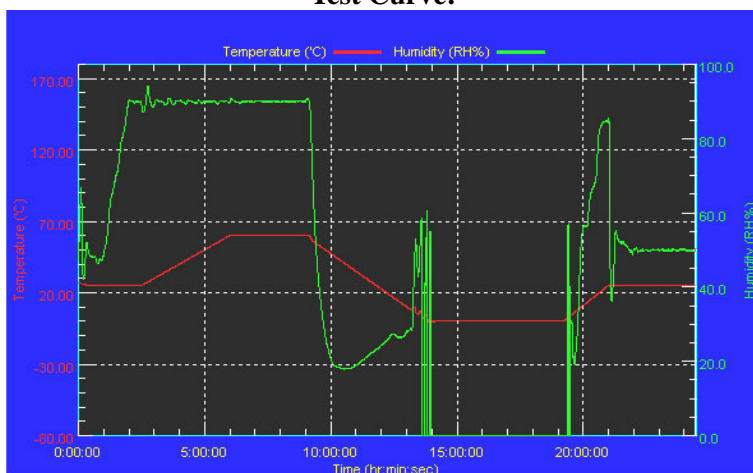
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/01/10  
Serial Number: 6488KT

**Temperature & Humidity Power On/Off Test:**

**Testing Specification:**

Step	Temperature (°C)	Humidity (%RH)	Duration (HH:MM)
1	25	50	00:30
2	25	50	00:30
3	25	90	01:00
4	25	90	00:30
5	60	90	03:30
6	60	90	03:00
7	0	0	04:50
8	0	0	05:23
9	25	50	01:47
10	25	50	03:00

**Test Curve:**



**Test Result:**

With DSL 1GB / ELPIDA E5108AJBG-6E-E / DDR2 667 Memory

No problem was found during the temperature & humidity power on/off test.

Test Method	Actual	Successful	Failure rate	On time	Off Time
Power On/Off	1393/times	1393/times	0%	33 Sec.	33 Sec.

**Test Date:** 07-22-2010

**Test Product:** RTC-1000D1

**Test Site:** AAEON QE Internal Lab.

**Temperature Measurement:**

40 Channel Thermal Recorder:  
YOKOGAWA Inc,  
Model: DA100-13-1D  
Date of Calibration: 12/08/09  
Serial Number: 12A323190

**Test Condition:**

Ambient temperature: 25dC  
Continuous running till thermal stability (within less than 1°C)

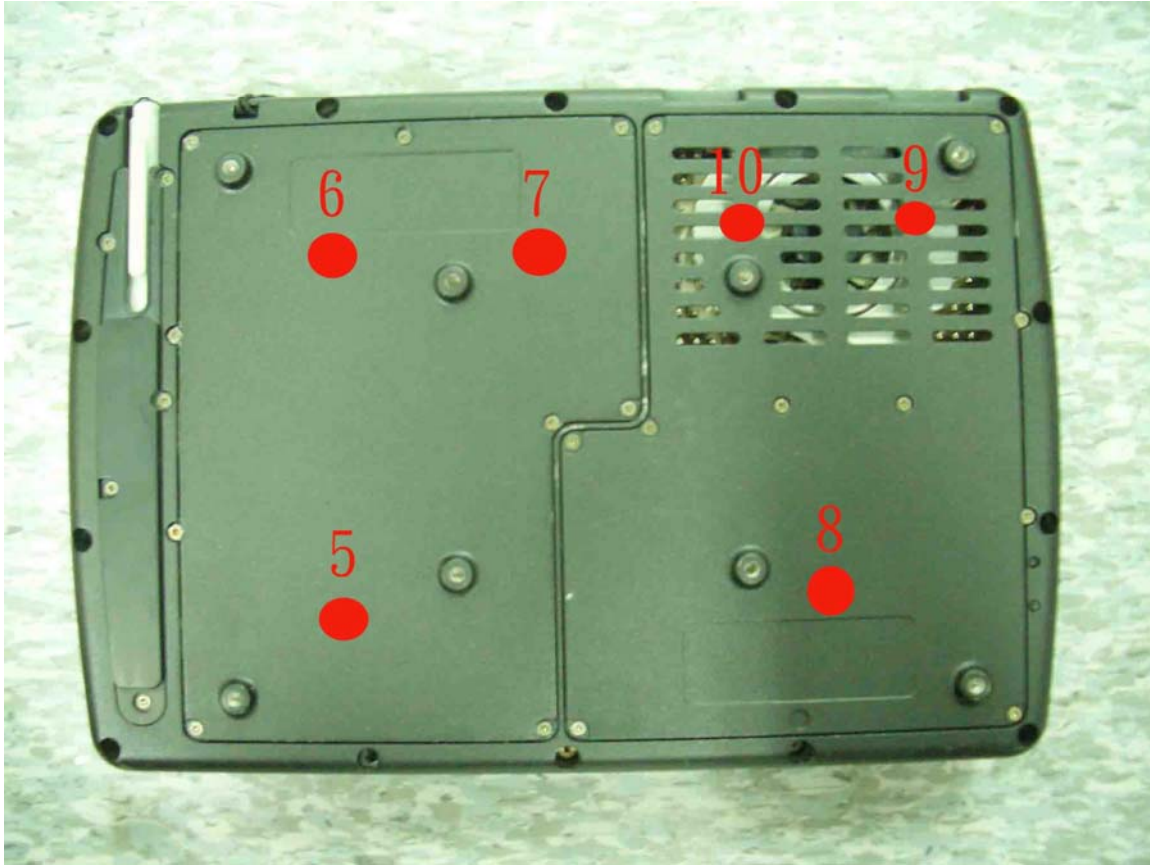
**Test Software:**

Windows XP Embedded / Run PassMark Burn In Test 4.0 Pro

**Terminal Recorder:**

Measuring Thermal Couple Position :





**Thermal profile data:**

**RTC-1000D1**

Point	Temp. Stage(°C)	Spec	25
1. Point 1		$\Delta T$ $\leq 20$ $^{\circ}C$	40.4
2. Point 2			42.8
3. Point 3			36.1
4. Point 4			36.2
5. Point 5 - Bottom of Battery			37.6
6. Point 6 - Bottom of Battery			38.2
7. Point 7 - Bottom of RAM			41.4
8. Point 8 - Bottom of HDD			42.6
9. Point 9 - Bottom of FAN (CPU)			44.5
10. Point 10 - Bottom of FAN (NB)			44.4
Room Temperature			25.1
<b>Any Tm value showed in red words which meaning the value over the Tc degree C of this device specification.</b>			

**Sample Configuration & Quantity Under Test:**

Quantity: 1 (RTC-1000D1)

**Test Result:**

No problem was found during the room temperature operation test.

# Temperature rise test

**Test Date:** 07-23-2010

**Test Product:** RTC-1000D1

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference EN 61131-2(94), UL508 (94)

**Temperature Measurement:**

40 Channel Thermal Recorder:  
YOKOGAWA Inc,  
Model: DA100-13-1D  
Date of Calibration: 12/08/09  
Serial Number: 12A323190

**Test Condition:**

Ambient temperature: 35dC  
Continuous running till thermal stability (within less than 1°C)

**Test Software:**

Windows XP Embedded / Run PassMark Burn In Test 4.0 Pro

**Thermal profile data:**

**RTC-1000D1**

Point	Temp. Stage(°C)	Spec	35	25
01. CPU		100	53.9	43.9
02. North Bridge		105	53.7	43.7
03. South Bridge		99	66.7	56.7
04. U13		70	66.5	56.5
05. L5		125	65.8	55.8
06. Q20		125	64.9	54.9
07. U45		70	64.5	54.5
08. WLAN		--	61.8	51.8
09. RAM ambient 1 - Between on board RAM & External RAM		95	59.5	49.5
10. RAM ambient 2 - Between External RAM & Bluetooth		95	59.4	49.4
11. EC3		105	54.6	44.6
12. C472		105	54.6	44.6
13. C413		85	53.1	43.1
14. U51		85	51.5	41.5
15. U54		70	66.3	56.3
16. HDD - Between main board& HDD		60	62.0	52.0
17. Chamber Air Temperature		N/A	35.0	25.0

**Any Tm value showed in red words which meaning the value over the Tc degree C of this device specification.**

**Sample Configuration & Quantity Under Test:**

Quantity: 1 (RTC-1000D1)

**Test Result:**

No problem was found during the temperature rise operation test. **But operation temperature of HDD was over the specification.**



**Test Date:** 06-23~30-2010

**Test Product:** RTC-1000D1 + RDS-141V

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference MIL-STD 810F Method 501.4 High Temperature  
Procedure I - Storage

**Test Equipment:**

Programmable Temperature & Humidity Chamber

K.SON. INS. TECH. CORP.

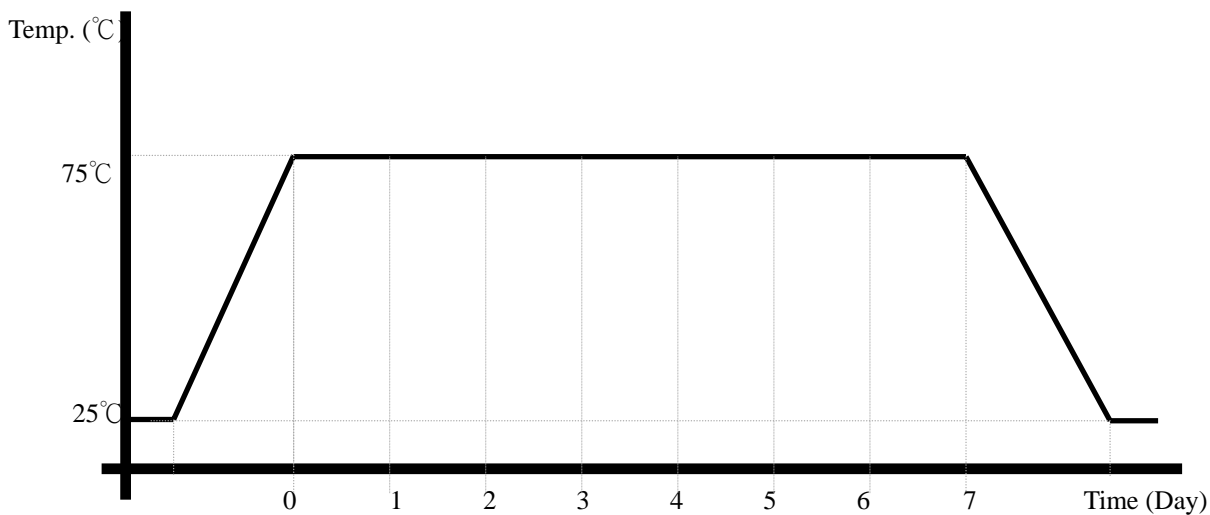
Model: THS-B6T-150+LN2

Date of Calibration: 04/01/10

Serial Number: 6487KT

**Testing Item:**

1. Test Temperature: 75°C
2. Test Time: 7days
3. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (RTC-1000D1 + RDS-141V)

**Test Result:**

No problem was found after the high temperature storage test.

**Test Date:** 07-01~07-2010

**Test Product:** RTC-1000D1 + RDS-141V

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference MIL-STD 810F Method 501.4 High Temperature  
Procedure II - Operation

**Test Equipment:**

Programmable Temperature & Humidity Chamber

K.SON. INS. TECH. CORP.

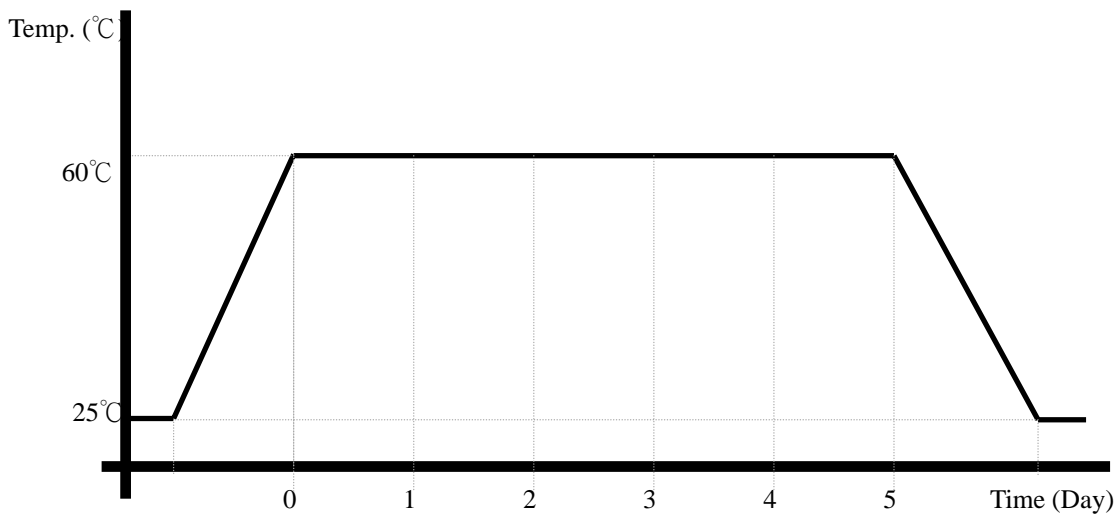
Model: THS-B6T-150+LN2

Date of Calibration: 04/01/10

Serial Number: 6487KT

**Testing Item:**

4. Test Temperature: 60°C
5. Test Time: 5days
6. Test Software: Windows XP Embedded / Run PassMark Burn In Test 4.0 Pro
7. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (RTC-1000D1 + RDS-141V)

**Test Result:**

No problem was found during the high temperature operation test.

**Test Date:** 07-07~08-2010

**Test Product:** RTC-1000D1 + RDS-141V

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference MIL-STD 810F Method 502.4 Low Temperature  
Procedure I - Storage

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/01/10  
Serial Number: 6487KT

**Testing Item:**

1. Test Temperature: -55°C
2. Test Times: 24Hrs
3. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (RTC-1000D1 + RDS-141V)

**Test Result:**  
No problem was found after the low temperature storage test.

**Test Date:** 07-08~09-2010

**Test Product:** RTC-1000D1 + RDS-141V

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference MIL-STD 810F Method 501.4 High Temperature  
Procedure II - Operation

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.

Model: THS-B6T-150+LN2

Date of Calibration: 04/01/10

Serial Number: 6487KT

**Testing Item:**

1. Test Temperature: -23°C
2. Test Times: 24Hrs
3. Test Software: Windows XP Embedded / Run PassMark Burn In Test 4.0 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (RTC-1000D1 + RDS-141V)

**Test Result:**

No problem was found during the low temperature operation test.

# Humidity test

**Test Date:** 07-09~19-2010

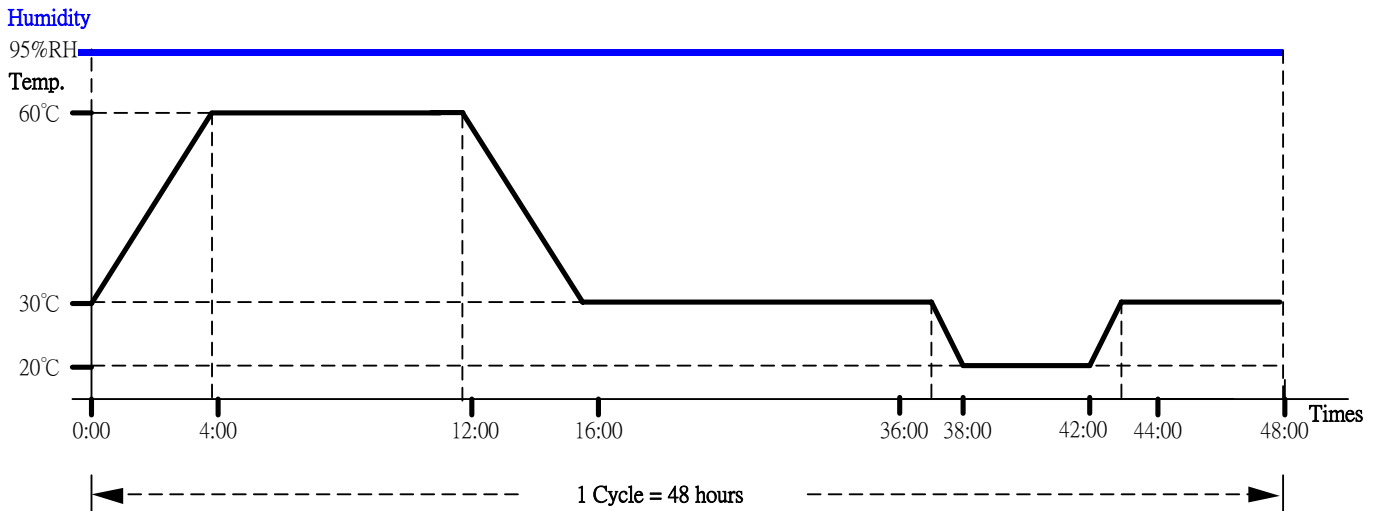
**Test Product:** RTC-1000D1 + RDS-141V

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference MIL-STD 810F Method 507.4 Testing procedures  
FIGURE 507.4-1. Aggravated temperature-humidity cycle

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/01/10  
Serial Number: 6487KT

- Test Condition:**
1. Test Humidity: 95%RH
  2. Test Temperature: 60°C / 30°C / 20°C
  3. Test Times: 48Hrs / Cycle
  4. Test Cycle: 5 Cycles
  5. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (RTC-1000D1 + RDS-141V)

**Test Result:**  
No problem was found after the humidity storage test.

**Test Date:** 07-21~22-2010

**Test Product:** RTC-1000D1 + RDS-141V

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference MIL-STD 810F Method 503.4 Temperature Shock  
Procedure I - Shock from constant extreme temperatures

**Test Equipment:**

Programmable Temperature & Humidity Chamber

K.SON. INS. TECH. CORP.

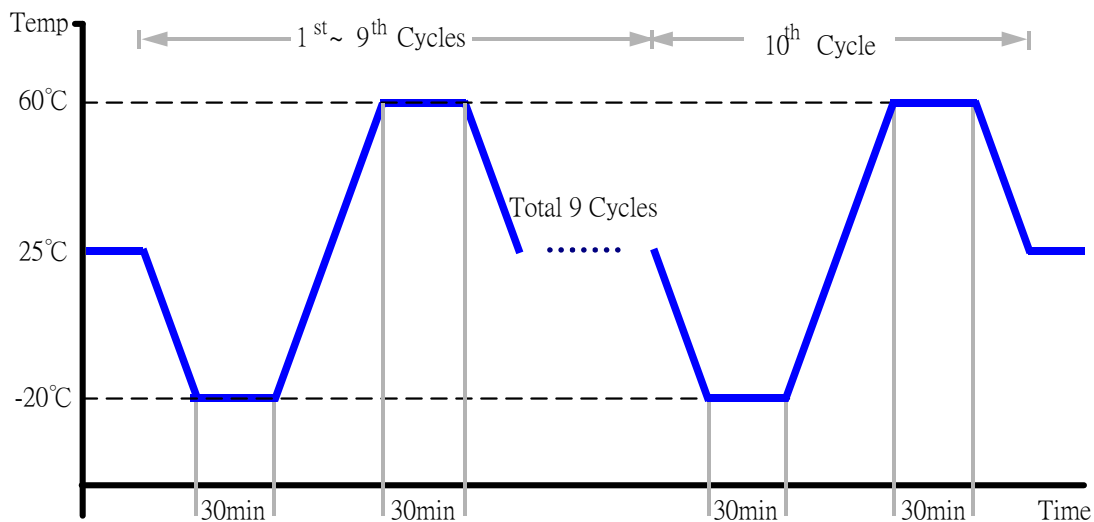
Model: THS-B6T-150+LN2

Date of Calibration: 04/01/10

Serial Number: 6488KT

**Test Condition:**

1. Test Low Temperature: -20°C
2. Test High Temperature: 60°C
3. Test dwell time: 30min
4. Temperature slope: 5 min
5. Test cycle: 10 cycles
6. Test Software: Windows XP Embedded / Run PassMark Burn In Test 4.0 Pro
7. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (RTC-1000D1 + RDS-141V)

**Test Result:**

No problem was found during the variation temperature operation test.

**Test Date:** 07-19~20-2010

**Test Product:** RTC-1000D1 + RDS-141V

**Test Site:** AAEON QE Internal Lab.

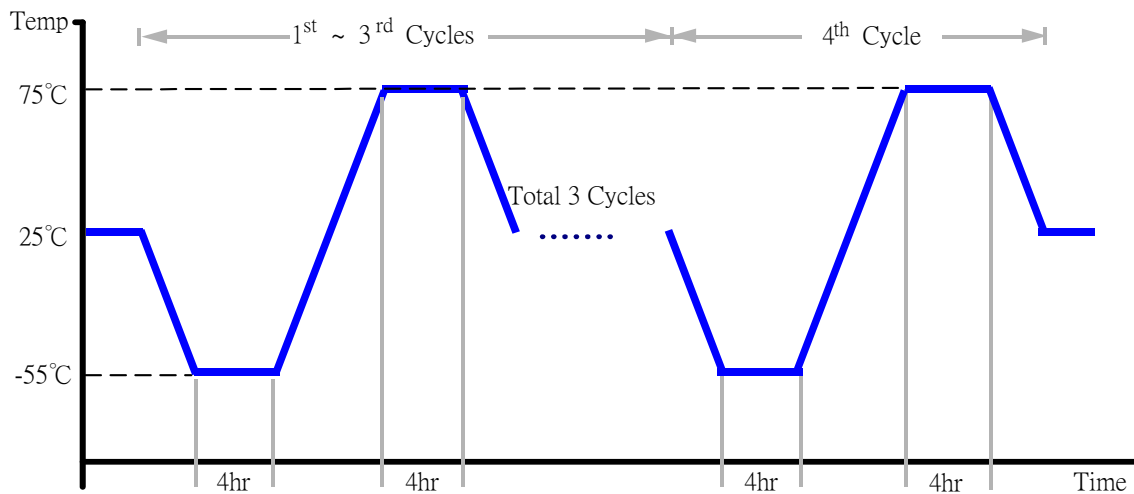
**Test Standard:** Reference MIL-STD 810F Method 503.4 Temperature Shock  
Procedure I - Shock from constant extreme temperatures

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/01/10  
Serial Number: 6488KT

**Test Condition:**

1. Test Low Temperature: -55°C
2. Test High Temperature: 75°C
3. Test dwell time: 4Hrs
4. Temperature slope: 10 min
5. Test cycle: 4 cycles
6. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (RTC-1000D1 + RDS-141V)

**Test Result:**

No problem was found after the variation temperature non-operation test.

# Cold start and hot start test

**Test Date:** 06-22~23-2010

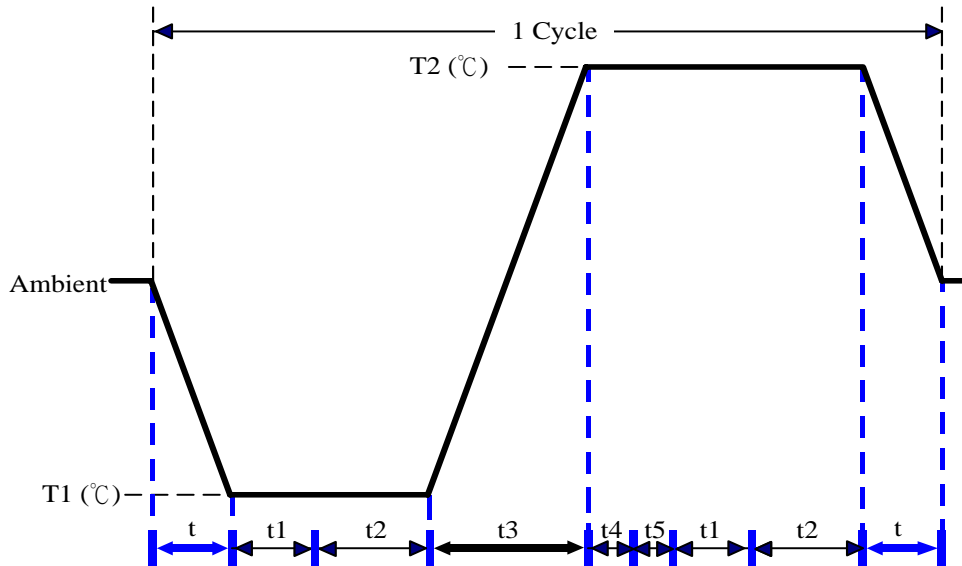
**Test Product:** RTC-1000D1 + RDS-141V

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference IEC 68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/01/10  
Serial Number: 6487KT

**Test Condition:**



Parameters	Description
T1	-5°C
T2	45°C
t1	1 hrs
t2	2 hrs
t4, t5	30 min
t, t3	2°C/min
n (Cycle)	1

t, t3 = temprature slope  
t, t1: Power Off  
t2: Power on/off test 5 times (on 2 min / off 5min)  
t3, t4: Run PassMark Burn In Test  
t5: Win XP Embedded Software restart test 2 times  
Test Software: Windows XP

**Test Result:**

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.